

C3M0280090D

Silicon Carbide Power MOSFET C3M MOSFET Technology

N-Channel Enhancement Mode

Features

- C3M SiC MOSFET technology
- High blocking voltage with low On-resistance
- · High speed switching with low capacitances
- Fast intrinsic diode with low reverse recovery (Qrr)
- Halogen free, RoHS compliant

Benefits

- Higher system efficiency
- Reduced cooling requirements
- Increased power density
- · Increased system switching frequency

Applications

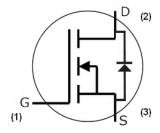
- Renewable energy
- Lighting
- High voltage DC/DC converters
- Telecom Power Supplies
- Induction Heating

Package









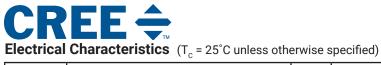
Part Number	Package	Marking		
C3M0280090D	TO-247-3	C3M0280090		

Maximum Ratings ($T_c = 25 \, ^{\circ}\text{C}$ unless otherwise specified)

Symbol	Parameter	Value	Unit	Test Conditions	Note
V _{DSmax}	Drain - Source Voltage	900	٧	V _{GS} = 0 V, I _D = 100 μA	
V_{GSmax}	Gate - Source Voltage (dynamic)	-8/+19	٧	AC (f >1 Hz)	Note: 1
V_{GSop}	Gate - Source Voltage (static)	-4/+15	٧	Static	Note: 2
	Continuous Drain Current	10.2	Α	V _{GS} = 15 V, T _C = 25°C	Fig. 19
I _D	Continuous Diam Current	6.8	_ ^	V _{GS} = 15 V, T _C = 100°C	
I _{D(pulse)}	Pulsed Drain Current	22	А	Pulse width t _P limited by T _{jmax}	Fig. 22
P _D	Power Dissipation	45	W	T _C =25°C, T _J = 150 °C	Fig. 20
T _J , T _{stg}	Operating Junction and Storage Temperature	-55 to +150	°C		
T _L	Solder Temperature	260	°C	1.6mm (0.063") from case for 10s	
M _d	Mounting Torque	1 8.8	Nm lbf-in	M3 or 6-32 screw	

Note (1): When using MOSFET Body Diode $V_{GSmax} = -4V/+19V$

Note (2): MOSFET can also safely operate at 0/+15 V



Symbol	Parameter	Min.	Тур.	Max.	Unit	Test Conditions	Note	
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	900			V	V _{GS} = 0 V, I _D = 100 μA		
\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \	Code Through ald Walter an	1.8	2.7	3.5	V	V _{DS} = V _{GS} , I _D = 1.2 mA	Fig. 11	
$V_{\text{GS(th)}}$	Gate Threshold Voltage		2.2		V	V _{DS} = V _{GS} , I _D = 1.2 mA, T _J = 150°C		
I _{DSS}	Zero Gate Voltage Drain Current		1	100	μΑ	V _{DS} = 900 V, V _{GS} = 0 V		
I _{GSS}	Gate-Source Leakage Current		10	250	nA	V _{GS} = 15 V, V _{DS} = 0 V		
R _{DS(on)}	Drain-Source On-State Resistance		320	360	mΩ	V _{GS} = 15 V, I _D = 7.5 A	Fig. 4,	
*DS(on)	brain source on state nesistance		416		11122	V _{GS} = 15 V, I _D = 7.5 A, T _J = 150°C	5, 6	
g fs	Transconductance		3.6		S	V _{DS} = 15 V, I _{DS} = 7.5 A	Fig. 7	
yrs	Transconductance		3.6		<u> </u>	V _{DS} = 15 V, I _{DS} = 7.5 A, T _J = 150°C	1 ig. 7	
C_{iss}	Input Capacitance		204					
C_{oss}	Output Capacitance		26		pF	$V_{GS} = 0 \text{ V, } V_{DS} = 600 \text{ V}$	Fig. 17, 18	
C_{rss}	Reverse Transfer Capacitance		3			f = 1 MHz Vac = 25 mV		
E _{oss}	C _{oss} Stored Energy		5.5		μJ	VAC - 25 IIIV	Fig. 16	
Eon	Turn-On Switching Energy (Body Diode FWD)		80		μJ	$V_{DS} = 400 \text{ V}, V_{GS} = -4 \text{ V}/15 \text{ V}, I_{D} = 7.5 \text{ A},$	Fig. 26, 29 Note 3	
E _{OFF}	Turn Off Switching Energy (Body Diode FWD)		6		μυ	$R_{G(ext)} = 2.5\Omega$, L= 201 μ H, $T_J = 150$ °C		
t _{d(on)}	Turn-On Delay Time		5.3				Fig. 27, 29 Note 3	
t _r	Rise Time		25]	$V_{DD} = 400 \text{ V}, V_{GS} = -4 \text{ V}/15 \text{ V}$ $I_D = 7.5 \text{ A}, R_{G(ext)} = 2.5 \Omega,$		
$t_{\text{d(off)}} \\$	Turn-Off Delay Time		8.5		ns	Timing relative to V _{DS}		
t _f	Fall Time		6.4]	inductive load		
$R_{G(int)}$	Internal Gate Resistance		23.5		Ω	f = 1 MHz, V _{AC} = 25 mV		
Q_gs	Gate to Source Charge		3.0			V _{DS} = 400 V, V _{GS} = -4 V/15 V	Fig. 12	
Q_{gd}	Gate to Drain Charge		2.9		nC	I _D = 7.5 A		
Q_g	Total Gate Charge		9.7			Per IEC60747-8-4 pg 21		

Reverse Diode Characteristics ($T_c = 25^{\circ}\text{C}$ unless otherwise specified)

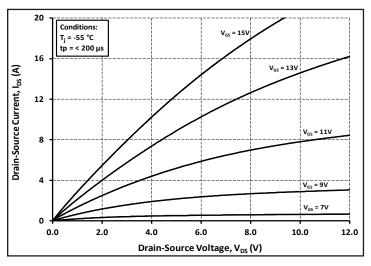
Symbol	Parameter	Тур.	Max.	Unit	Test Conditions	Note	
V_{SD}	Diode Forward Voltage	4.8		V	V _{GS} = -4 V, I _{SD} = 4 A	Fig. 8, 9, 10	
		4.4		٧	V _{GS} = -4 V, I _{SD} = 4 A, T _J = 150 °C		
Is	Continuous Diode Forward Current		9	Α	V _{GS} = -4 V	Note 1	
I _{S, pulse}	Diode pulse Current		22	Α	V _{GS} = -4 V, pulse width t _P limited by T _{jmax}	Note 1	
t _{rr}	Reverse Recover time	24		ns			
Q _{rr}	Reverse Recovery Charge	74		nC	V _{SS} = -4 V, I _{SD} = 7.5 A, V _R = 400 V dif/dt = 775 A/µs, T _J = 150 °C	Note 1	
I _{rrm}	Peak Reverse Recovery Current	4		А			

Thermal Characteristics

Symbol	Parameter	Max.	Unit	Test Conditions	Note
R _{eJC}	Thermal Resistance from Junction to Case	2.8			F: 04
R _{0JA} Thermal Resistance From Junction to Ambient		40	°C/W		Fig. 21

Note (3): Turn-off and Turn-on switching energy and timing values measured using SiC MOSFET Body Diode





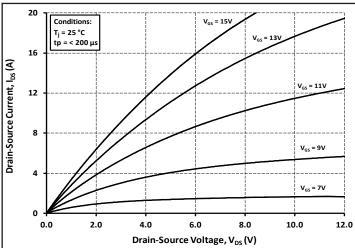
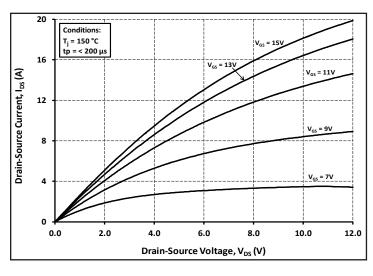


Figure 1. Output Characteristics T_J = -55 °C





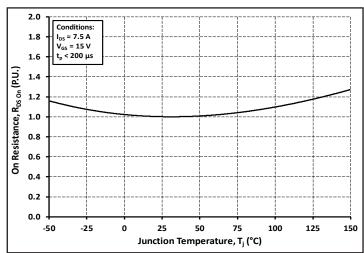
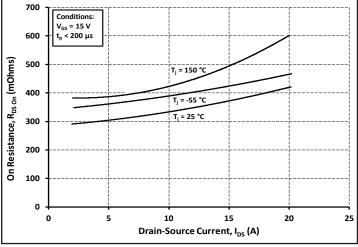


Figure 3. Output Characteristics T_J = 150 °C

Figure 4. Normalized On-Resistance vs. Temperature



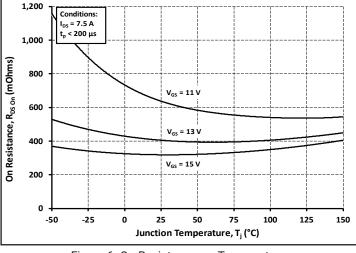
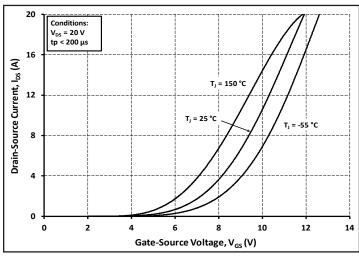


Figure 5. On-Resistance vs. Drain Current For Various Temperatures

Figure 6. On-Resistance vs. Temperature For Various Gate Voltage





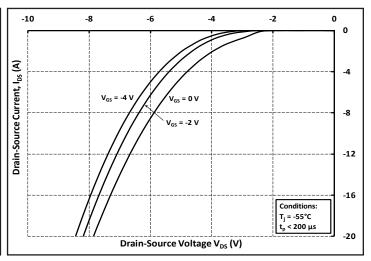
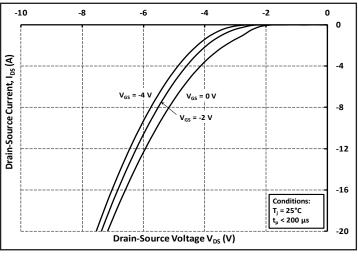


Figure 7. Transfer Characteristic for Various Junction Temperatures

Figure 8. Body Diode Characteristic at -55 °C



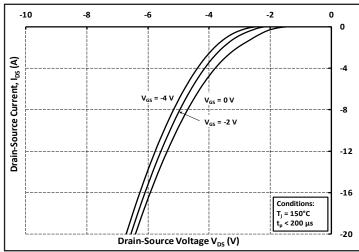
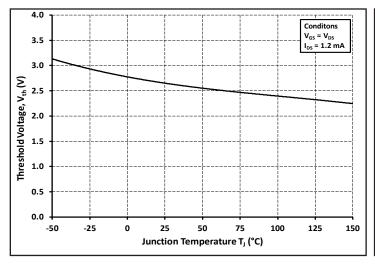


Figure 9. Body Diode Characteristic at 25 °C

Figure 10. Body Diode Characteristic at 150 °C



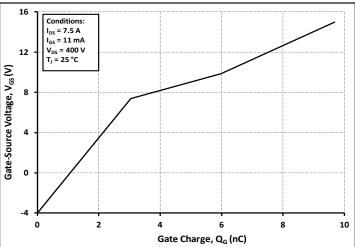
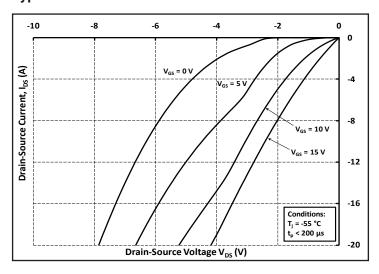


Figure 11. Threshold Voltage vs. Temperature

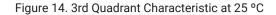
Figure 12. Gate Charge Characteristics

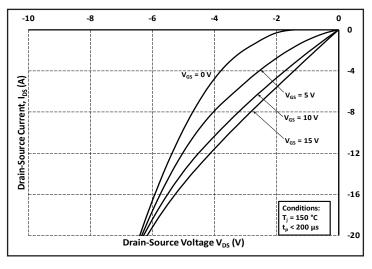




 $V_{GS} = 0 \ V$ $V_{GS} = 10 \ V$ $V_{GS} = 15 \ V$ $V_{GS} = 20 \ V$

Figure 13. 3rd Quadrant Characteristic at -55 °C





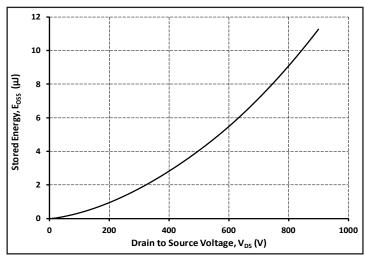
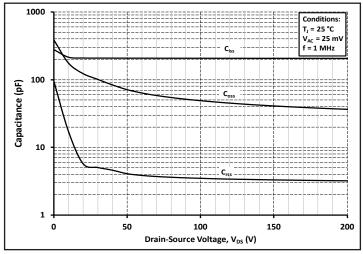


Figure 15. 3rd Quadrant Characteristic at 150 °C





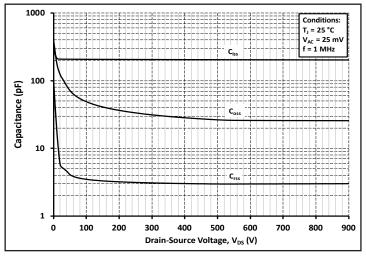


Figure 17. Capacitances vs. Drain-Source Voltage (0 - 200V)

Figure 18. Capacitances vs. Drain-Source Voltage (0 - 900V)



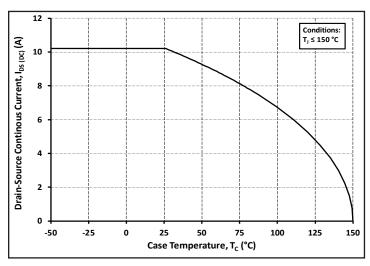


Figure 19. Continuous Drain Current Derating vs.
Case Temperature

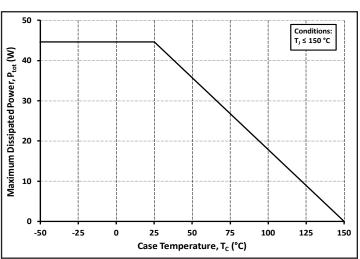


Figure 20. Maximum Power Dissipation Derating vs.

Case Temperature

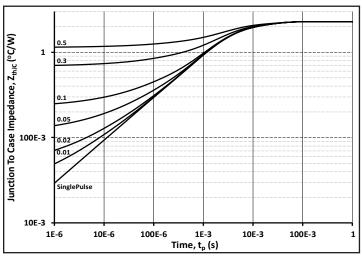


Figure 21. Transient Thermal Impedance (Junction - Case)

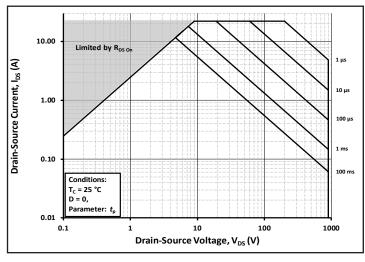


Figure 22. Safe Operating Area

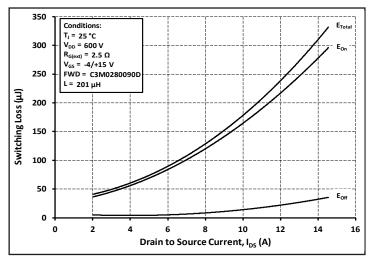


Figure 23. Clamped Inductive Switching Energy vs. Drain Current ($V_{DD} = 600V$)

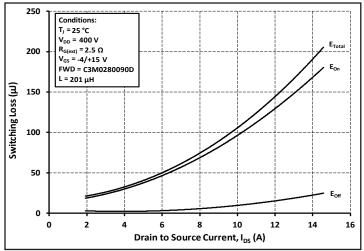
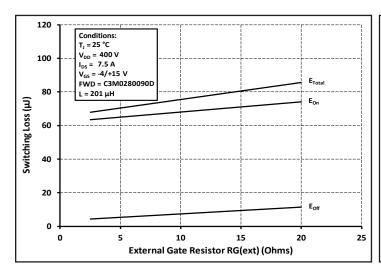


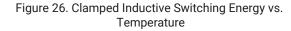
Figure 24. Clamped Inductive Switching Energy vs. Drain Current (V_{DD} = 400V)

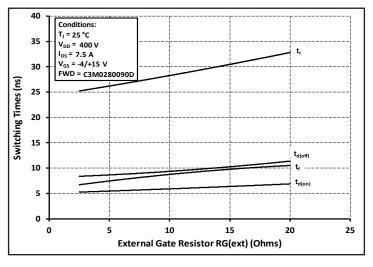




Conditions: I_{DS} = 7.5 A V_{DD} = 400 V 120 $R_{G(ext)} = 2.5 \Omega$ $V_{GS} = -4/+15 V$ 100 L = 201 μH FWD = C3M0280090D Switching Loss (知) 80 60 40 20 0 25 75 100 125 150 175 Junction Temperature, T_J (°C)

Figure 25. Clamped Inductive Switching Energy vs. $R_{G(ext)}$





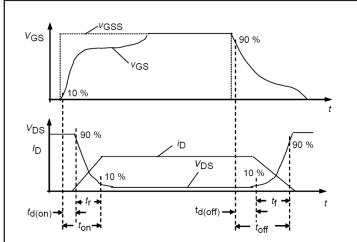


Figure 27. Switching Times vs. $R_{G(ext)}$

Figure 28. Switching Times Definition



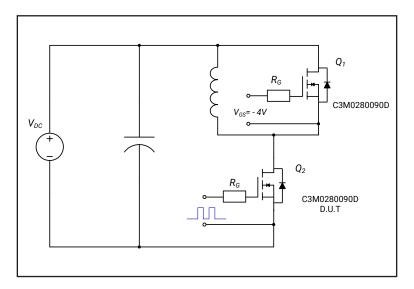


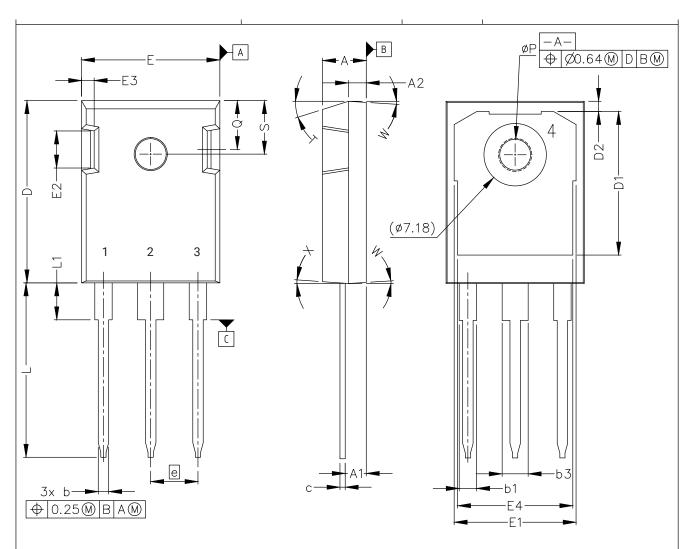
Figure 29. Clamped Inductive Switching Test Circuit

Note (3): Turn-off and Turn-on switching energy and timing values measured using SiC MOSFET Body Diode as shown above.



Package Dimensions

Package TO-247-3



NOTE

- 1. ALL METAL SURFACES: TIN PLATED, EXCEPT AREA OF CUT
- 2. DIMENSIONING & TOLERANCEING CONFIRM TO ASME Y14.5M-1994.
- 3. ALL DIMENSIONS ARE IN MILLIMETERS. ANGLES ARE IN DEGREES.
- 4. THIS DRAWING WILL MEET ALL DIMENSIONS REQUIREMENT OF JEDEC outlines TO-247 AD.
- 5. DIMENSION DO NOT INCLUDE BURR OR MOLD FLASH.
- 1 GATE
- 2 DRAIN
- 3 SOURCE
- 4 DRAIN

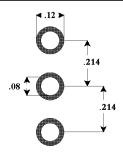


Package Dimensions

Package TO-247-3

CVII	MILLIMI	ETERS	INCHES			
SYM	MIN	MAX	MIN	MAX		
A	4.83	5.21	.190	.205		
A1	2.29	2.54	.090	.100		
A2	1.91	2.16	.075	.085		
b	1.07	1.33	.042	.052		
b1	1.91	2.41	.075	.095		
b3	2.87	3.38	.113	.133		
c	0.55	0.68	.022	.027		
D	20.80	21.10	.819	.831		
D1	16.25	17.65	.640	.695		
D2	0.95	1.25	.037	.049		
E	15.75	16.13	.620	.635		
E1	13.10	14.15	.516	.557		
E2	3.68	5.10	.145	.201		
E3	1.00	1.90	.039	.075		
E4	12.38	13.43	.487	.529		
e	5.44 BSC		.214 BSC			
N	3		3			
L	19.81	20.32	.780	.800		
L1	4.10	4.40	.161	.173		
ΦP	3.51	3.65	.138	.144		
Q	5.49	6.00	.216	.236		
S	6.04	6.30	.238	.248		
T	17.5° REF.					
W	3.5° REF.					
X	4° REF.					

Recommended Solder Pad Layout





Notes

RoHS Compliance

The levels of RoHS restricted materials in this product are below the maximum concentration values (also referred to as the threshold limits) permitted for such substances, or are used in an exempted application, in accordance with EU Directive 2011/65/EC (RoHS2), as implemented January 2, 2013. RoHS Declarations for this product can be obtained from your Cree representative or from the Product Documentation sections of www.cree.com.

REACh Compliance

REACh substances of high concern (SVHCs) information is available for this product. Since the European Chemical Agency (ECHA) has published notice of their intent to frequently revise the SVHC listing for the foreseeable future, please contact a Cree representative to insure you get the most up-to-date REACh SVHC Declaration. REACh banned substance information (REACh Article 67) is also available upon request.

This product has not been designed or tested for use in, and is not intended for use in, applications implanted into the human body
nor in applications in which failure of the product could lead to death, personal injury or property damage, including but not limited
to equipment used in the operation of nuclear facilities, life-support machines, cardiac defibrillators or similar emergency medical
equipment, aircraft navigation or communication or control systems, air traffic control systems.

Related Links

- SPICE Models: http://wolfspeed.com/power/tools-and-support
- SiC MOSFET Isolated Gate Driver reference design: http://wolfspeed.com/power/tools-and-support
- SiC MOSFET Evaluation Board: http://wolfspeed.com/power/tools-and-support